

Multi-track efficiency

➤ Outline

- **Review:**

 - Multi-track efficiency systematic study

 - Data quality check

- **New for VDC efficiency:**

 - a. One-track VDC misconstruction

 - b. Add electron+ background cut

 - c. New sample

Review

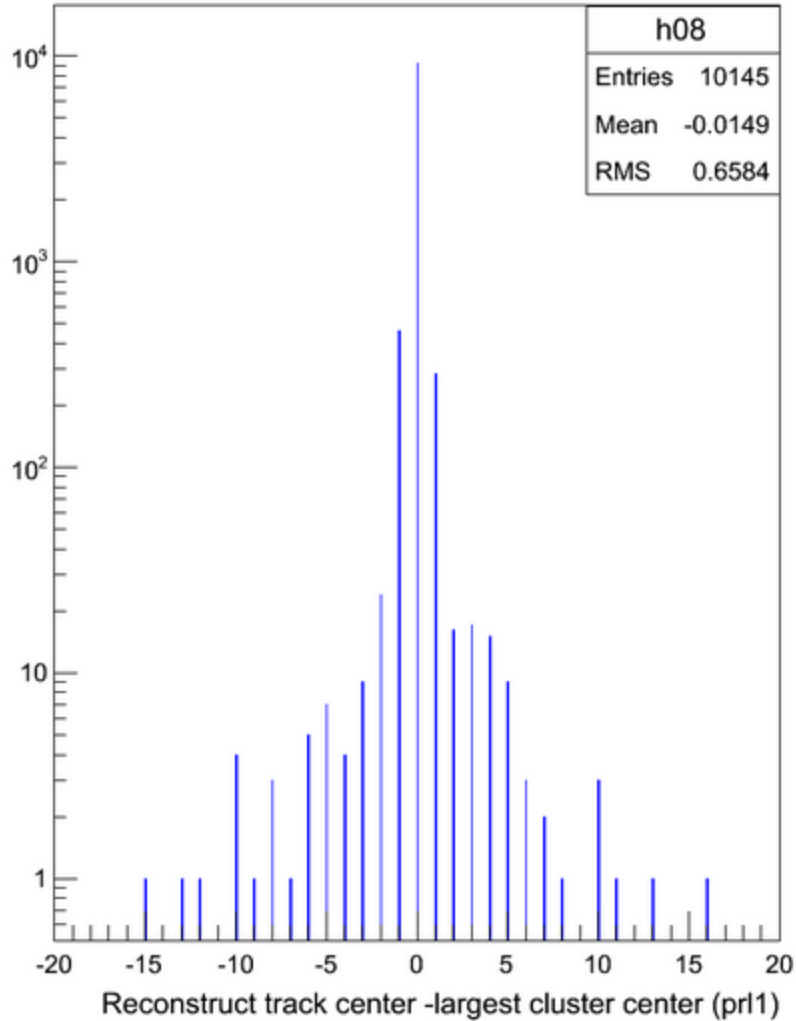
Settings: E=1157MeV P=1081.97MeV
RUN# 5039

- Track probability in electron sample for 1.157GeV, 1081.97MeV, 2.5T

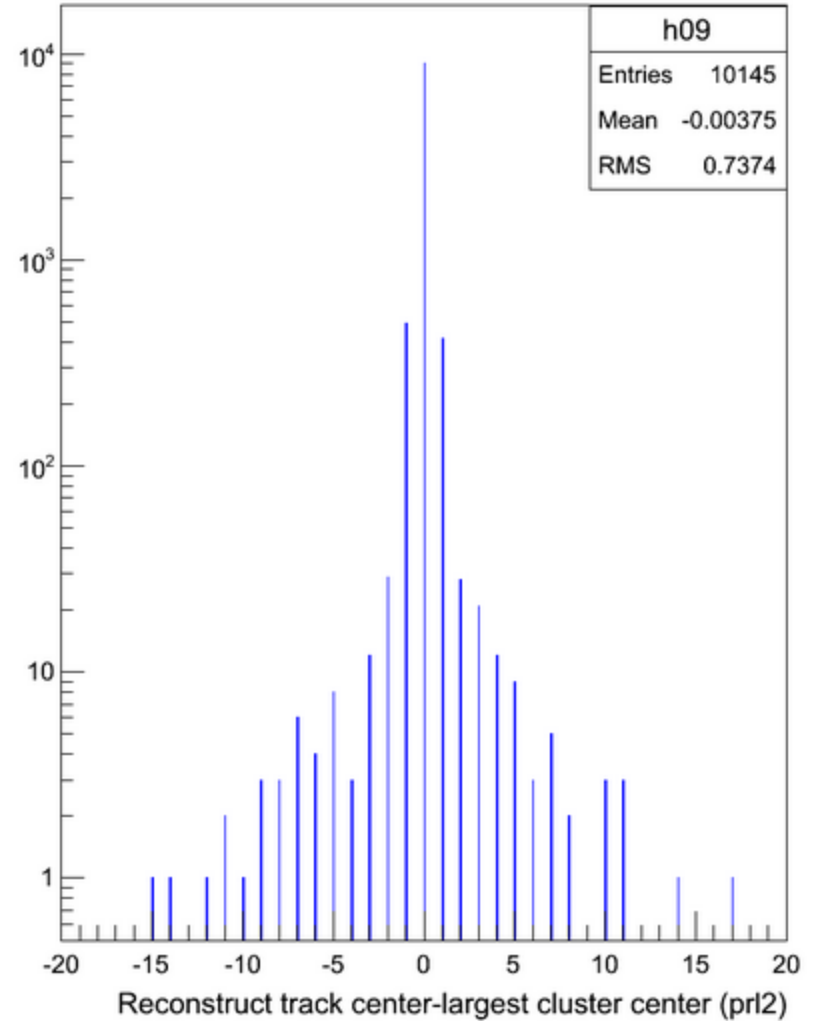
Number of tracks	0	1	2	3	4	5	6	7	More than 7
LHRS	0.00107	0.70016	0.18626	0.07471	0.02331	0.00894	0.00339	0.00135	0.00081

- Total Events Efficiency & uncertainty:**
- $97.2\%(eff)$ $\left\{ \begin{array}{l} - 1.2\%(sys.) \\ +0.2\%(sys.) \end{array} \right.$
- Not include one-track systematic

h08

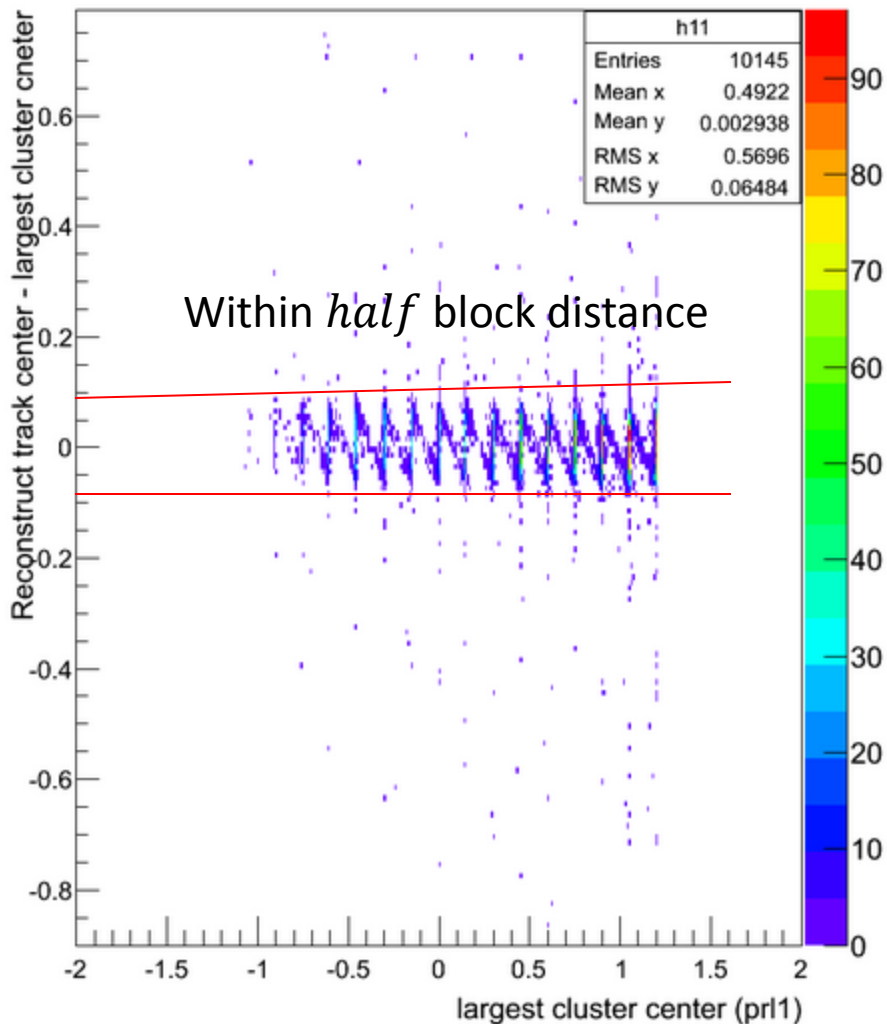


h09

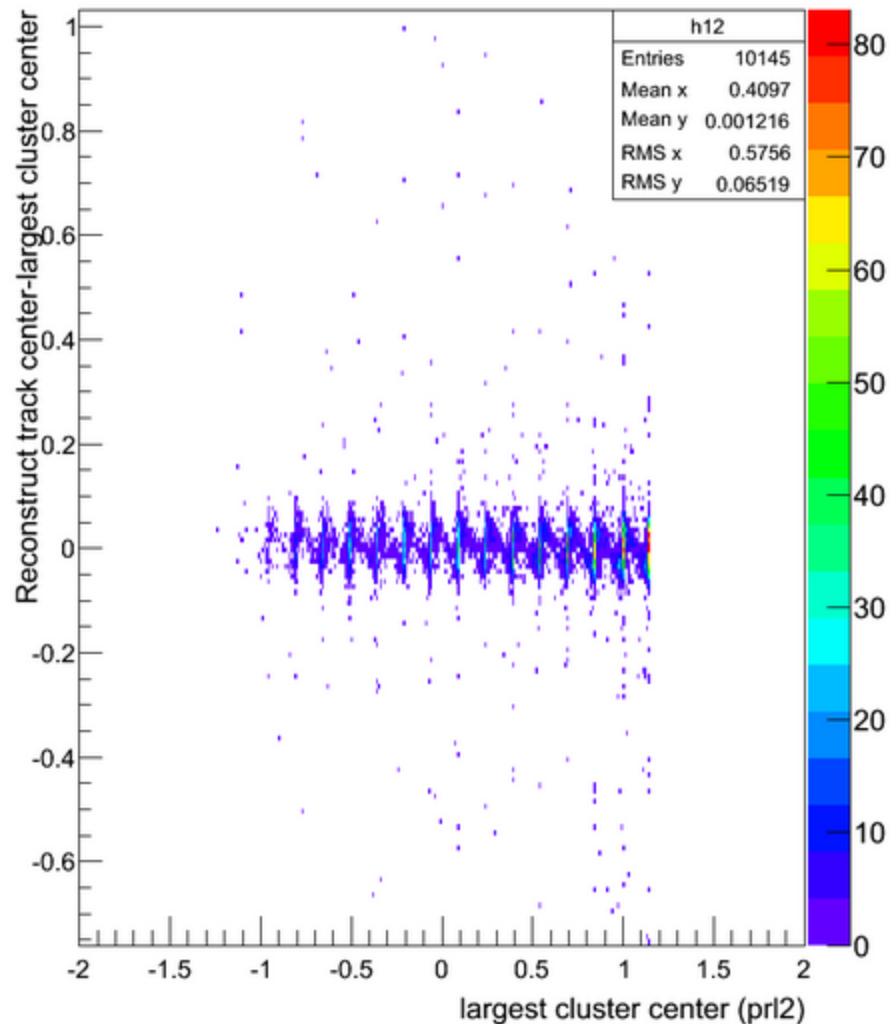


~ 1.4% of one track (with electron cuts) are not aligned in pr11, VDC misconstruction

h11



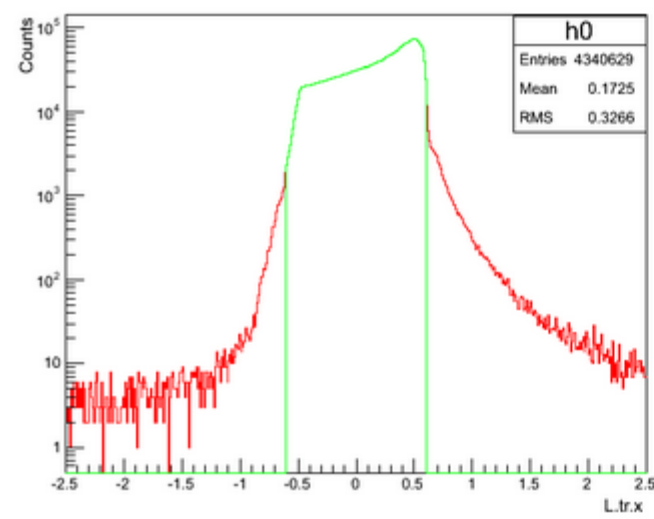
h12



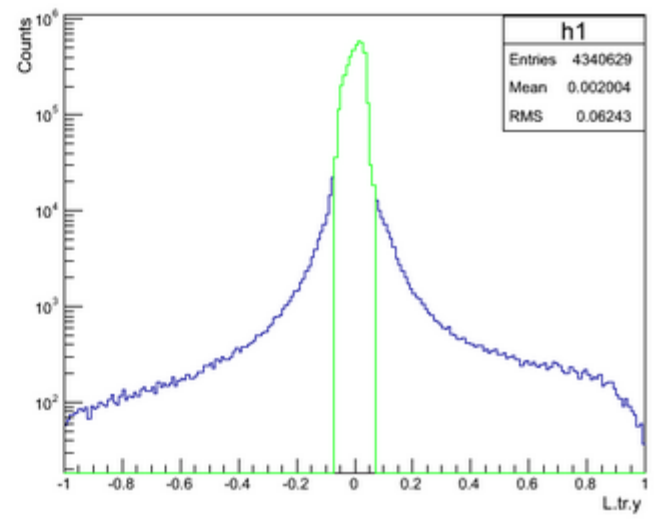
Comparison :
one track reconstructed cluster center VS. Largest cluster center

Acceptance cut

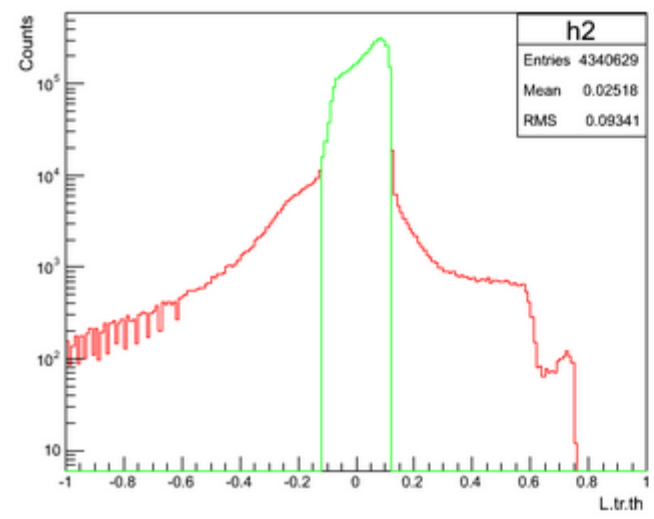
L.tr.x for runnum 5039



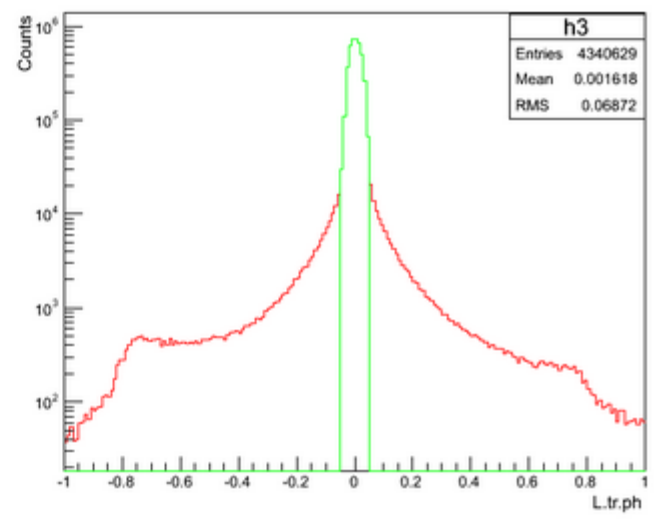
L.tr.y for runnum 5039



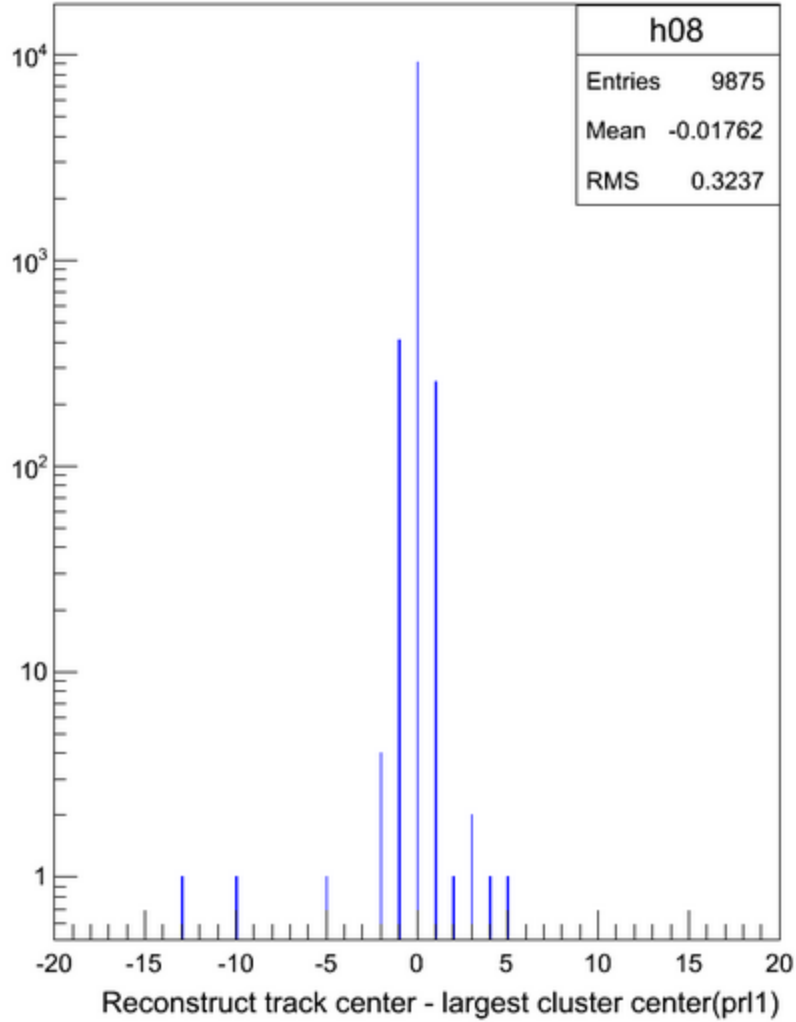
L.tr.th for runnum 5039



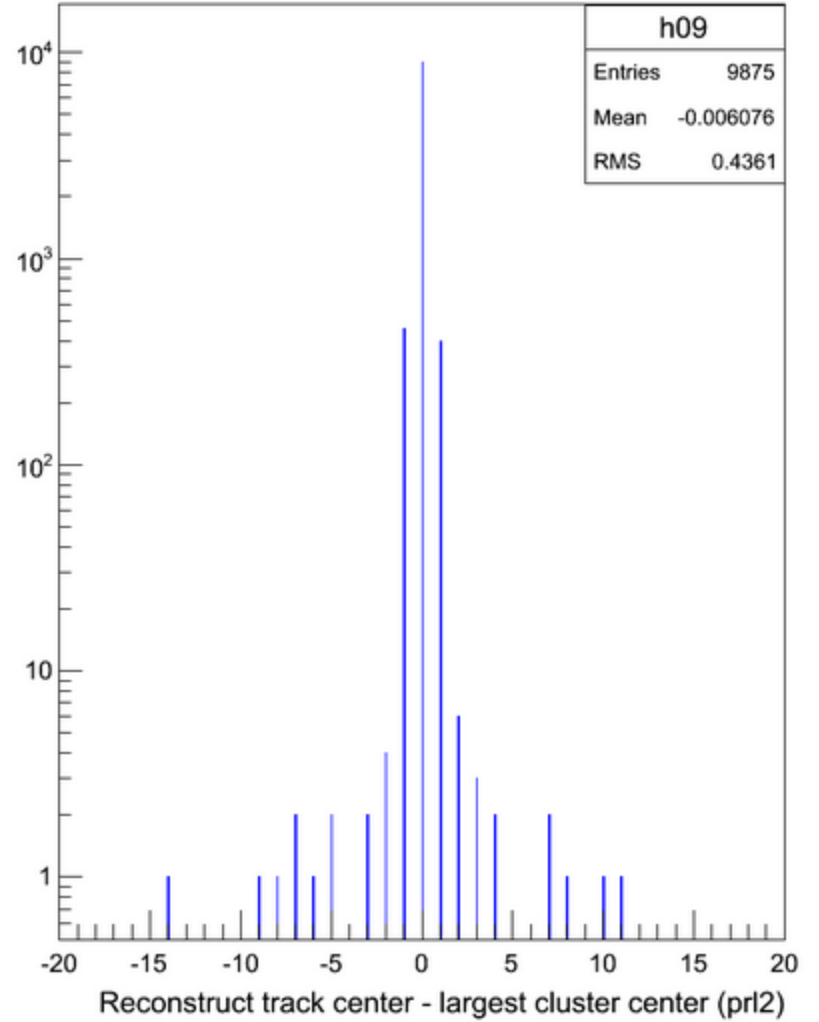
L.tr.ph for runnum 5039



h08



h09



99.9% are aligned with acceptance cuts to sample in pr1

Previous study

➤ Step

Electron sample $\xrightarrow{\text{Reconstruct in lead glass}}$ at-least-one-good track probability



❑ Sample selection rule:

- Cerenkov cut:
L.cer.asum_c>200
- Pion rejector cuts:
L.prl1.e>prl1_cut
Etot>Etot_cut
- No any other track information



❑ PID cuts:

At-least-one track satisfy:

- Cerenkov cut:
L.cer.asum_c>200
- Pion rejector cuts:
L.prl1.e>prl1_cut
Etot>Etot_cut

Now

➤ Step

Electron sample $\xrightarrow{\text{Reconstruct in lead glass}}$ at-least-one-good track probability



❑ Sample selection rule:

- Cerenkov cut:
L.cer.asum_c > 200
- Pion rejector cuts:
L.prl1.e > prl1_cut
Etot > Etot_cut
- **At least one track within acceptance**



❑ PID cuts:

At-least-one track satisfy:

- Cerenkov cut:
L.cer.asum_c > 200
- Pion rejector cuts:
L.prl1.e > prl1_cut
Etot > Etot_cut
- **This track should within acceptance cut**

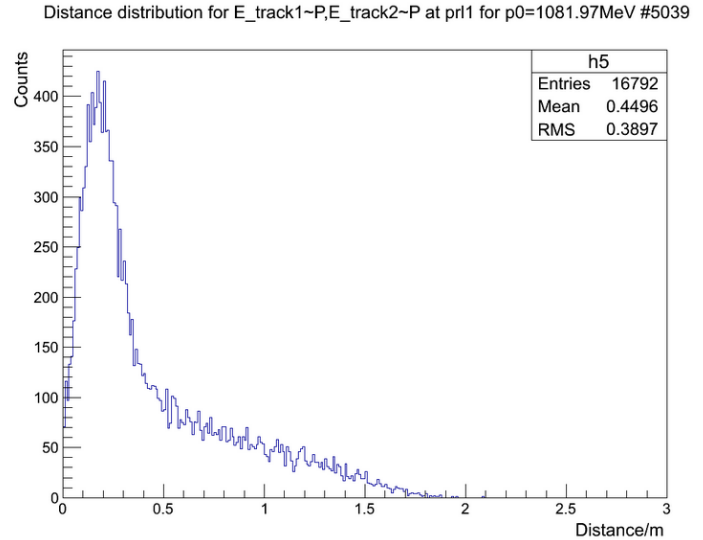
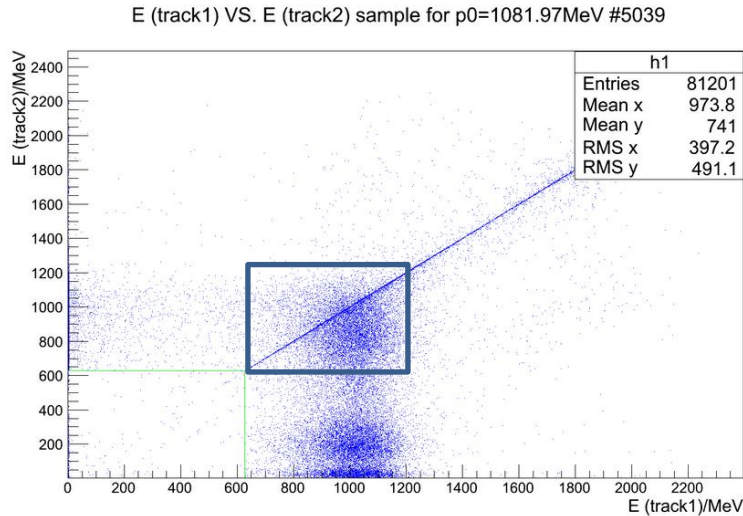
One track efficiency

One track study	Efficiency of all track events	inefficiency
Now	71.44%	0.39%
Previous	70.01%	1.41%

Now the sample is much more clean

Last time

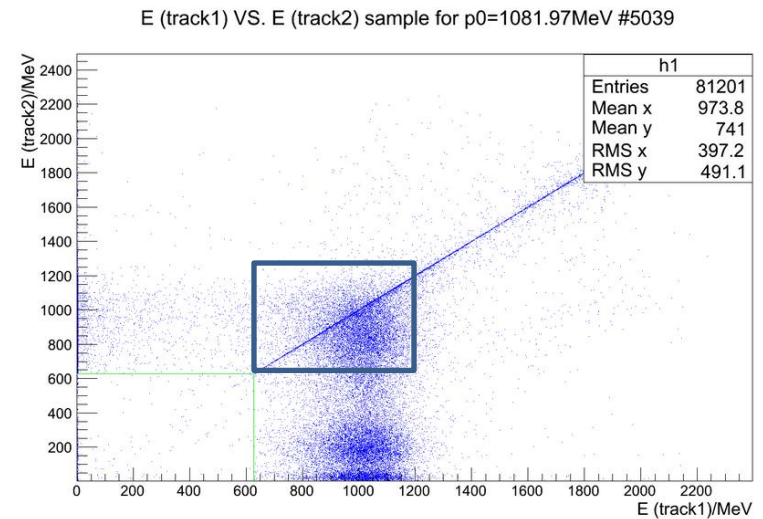
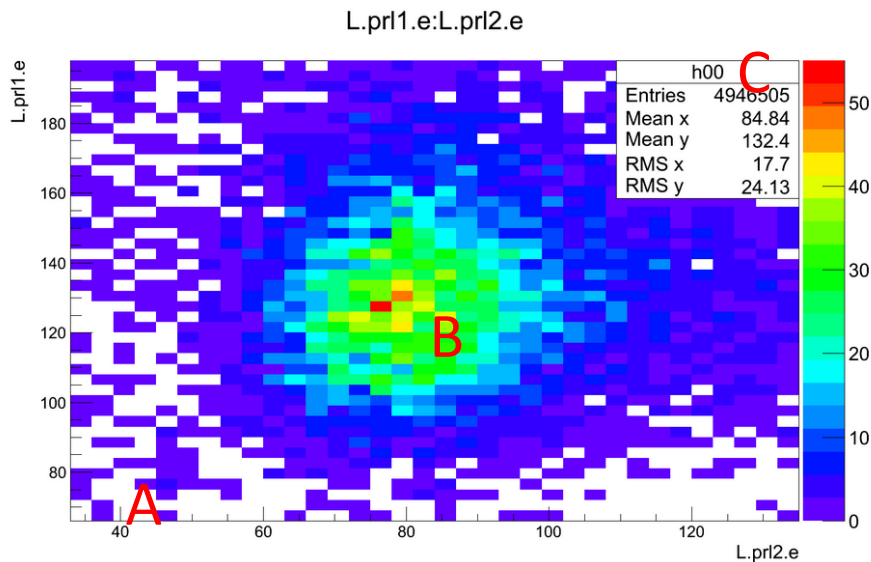
RUN# 5039



- Consider two tracks are very close and within one block distance, put into uncertainty \longrightarrow **Method 1**
- events: 0.099 of two-track events (0.018 of total track events)
- Method 1: contribute uncertainty 0.9% (half of 0.018)



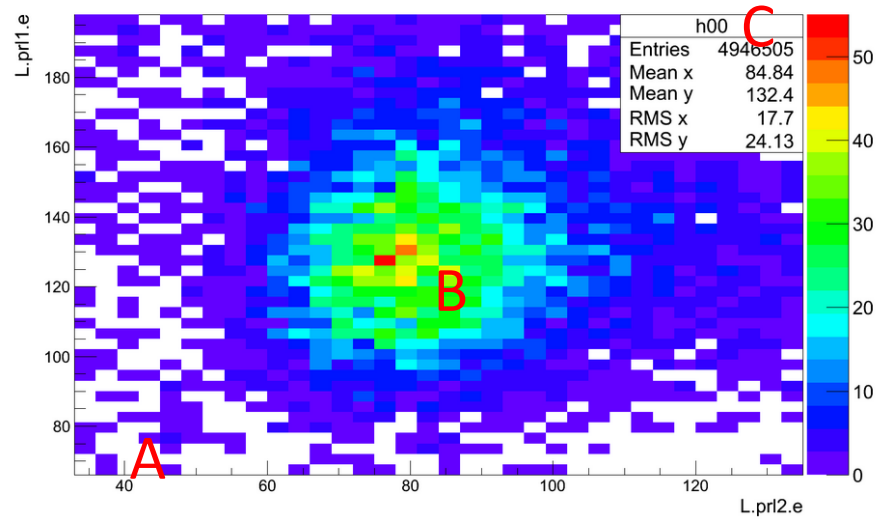
Electron + background cut



- Electron cut+ background Cut @B
- Good track satisfy
- ✓ $L.pr1.e > pr1_cut$ (electron)+ $pr1_cut$ (B)
- ✓ $Etot > Etot_cut$ (electron) + $Etot_cut$ (B)
- ✓ within acceptance cuts
- ✓ Applied to the track within one block distance

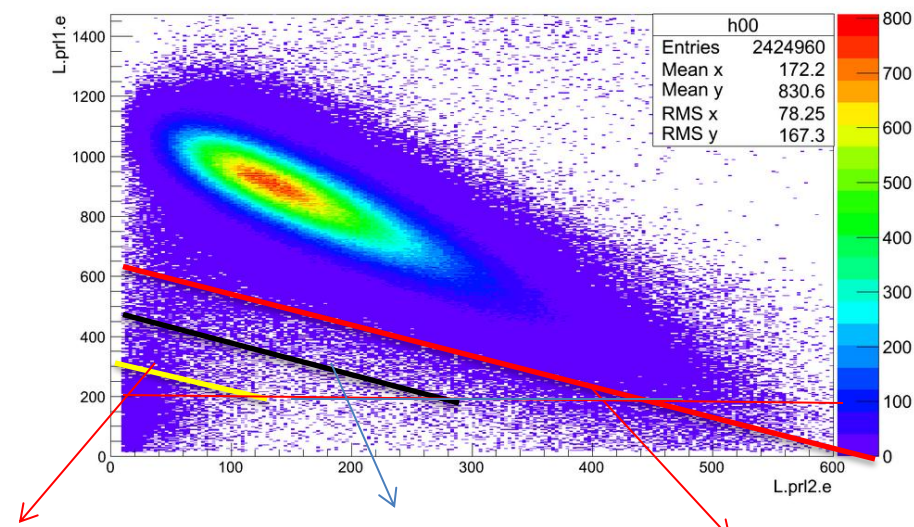
Strong pion background

L.pr1.e:L.pr2.e



Weak background

L.pr1.e:L.pr2.e



One background cut Average electron and background cut One electron cut

Apply to the events with one-block in the square (1.8% of total sample)

- Electron cut + background cut@ A
1.74% satisfied (0.06% inefficiency)
- Electron cut + background cut@ B
1.66% satisfied (0.14% inefficiency)
- Electron cut + background cut@ C
1.39% satisfied (0.41 % inefficiency)

17.73% $\left\{ \begin{array}{l} +0.14\%(sys.) \\ -0.27\%(sys.) \end{array} \right.$

NEW

Settings: E=1157MeV P=1081.97MeV

RUN# 5039

Number of tracks	1	2	3	4	5	6	7	More than 7
LHRS	0.71446	0.18068	0.07142	0.02105	0.00762	0.00283	0.00108	0.00086

- Total Events Efficiency & uncertainty:**

- Optional 1: 98.30%(*eff*) $\left[\begin{array}{l} - 0.59\%(sys.) \\ +0.49\%(sys.) \end{array} \right]$ Only center value consider one-track inefficiency.
No sys. Put on one-track efficiency

- Optional 2: 98.30%(*eff*) $\left[\begin{array}{l} - 0.59\%(sys.) \\ +0.49\%(sys.) + 0.39\% (one\ track\ ineff.) \end{array} \right]$

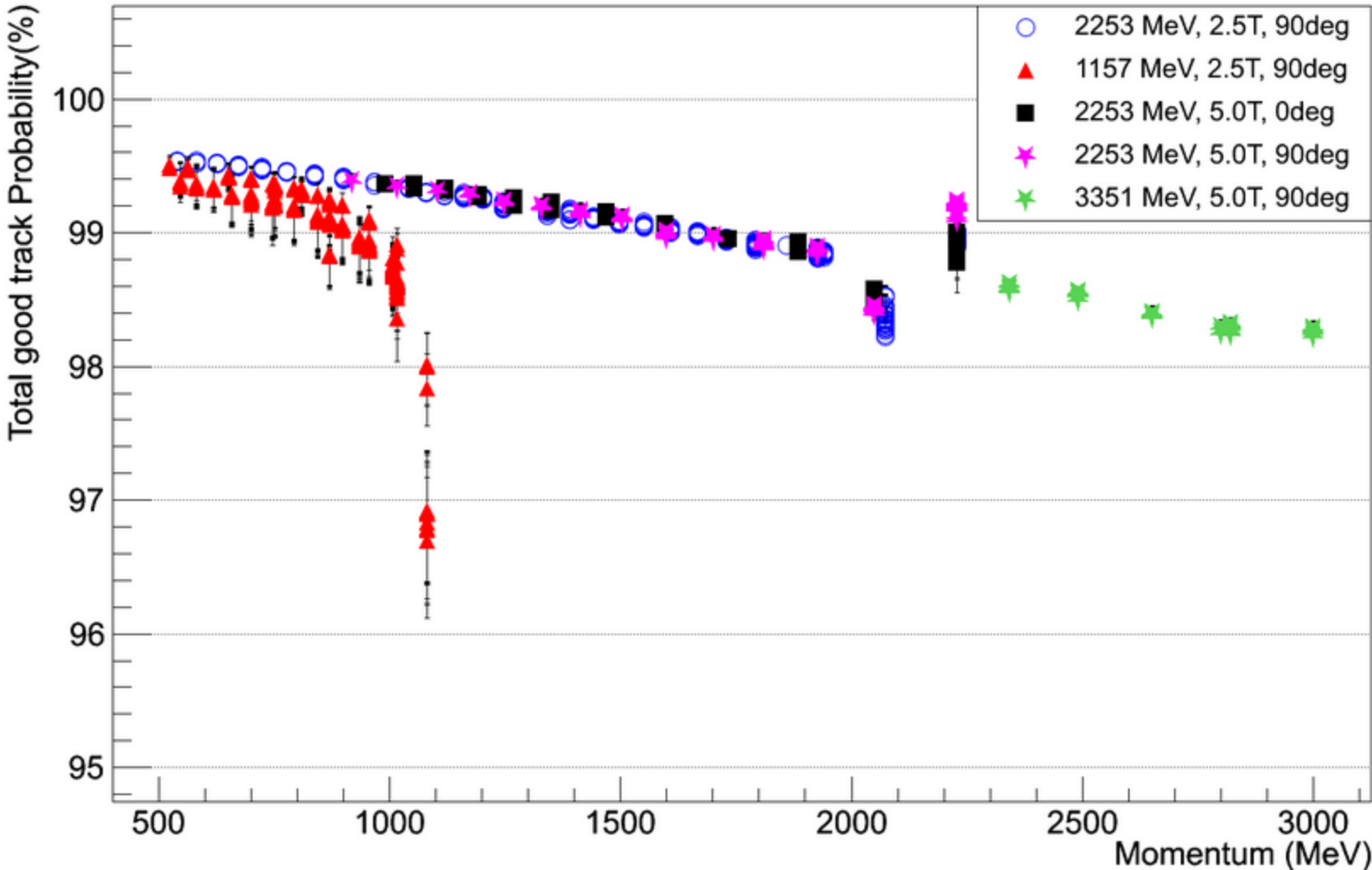
- Optional 3: 98.50%(*eff*) $\left[\begin{array}{l} - 0.59\%(sys.) - 0.20\% (half\ of\ one\ track\ ineff.) \\ +0.49\%(sys.) + 0.20\% (half\ of\ one\ track\ ineff.) \end{array} \right]$

- Optional 4: 98.30%(*eff*) $\left[\begin{array}{l} - 0.59\%(sys.) - 0.39\% (one\ track\ ineff.) \\ +0.49\%(sys.) + 0.39\% (one\ track\ ineff.) \end{array} \right]$

Option 2-4 is loose.

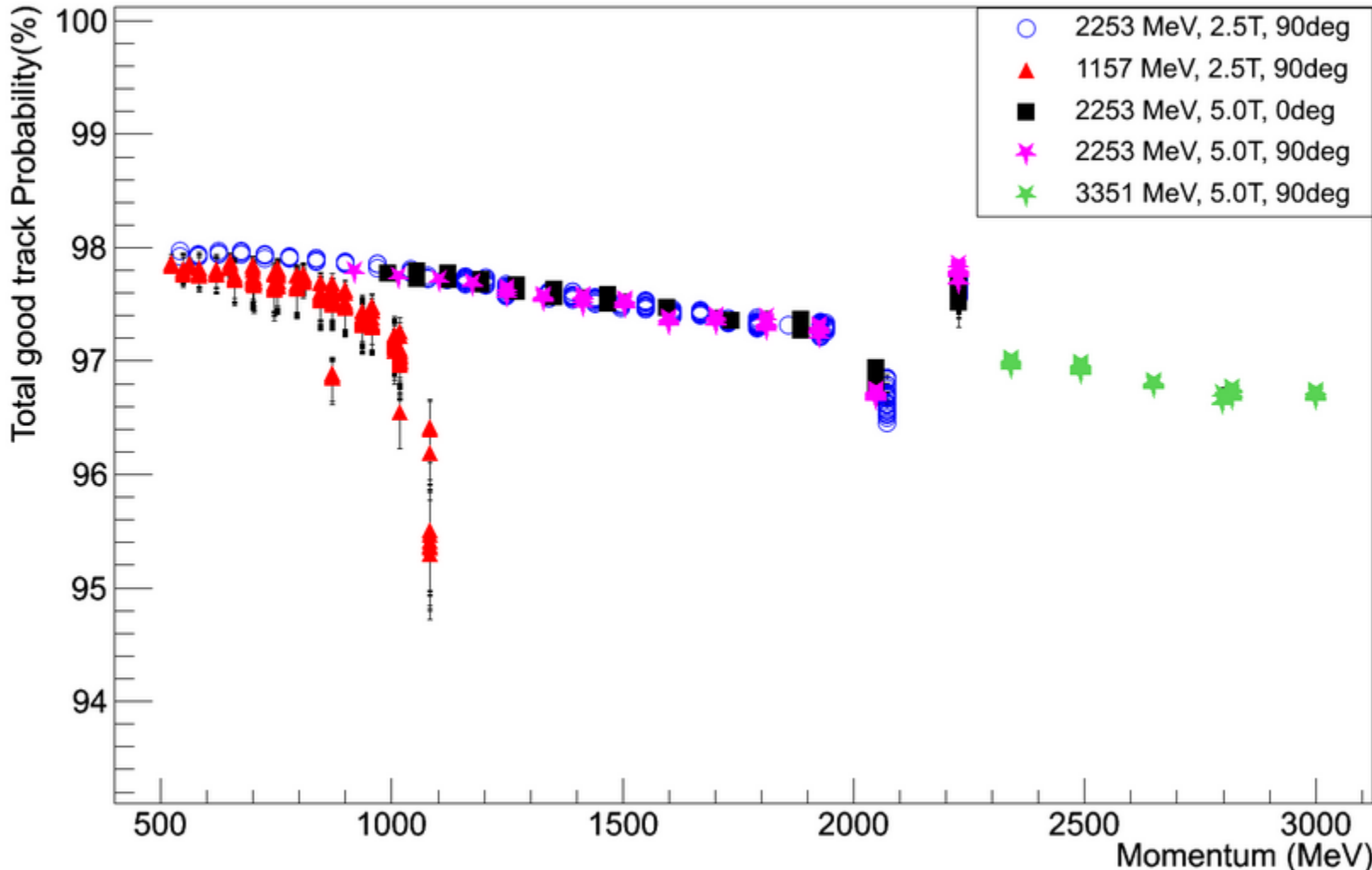
Previous study with background cuts added: center value not consider one-track inefficiency

LHRS VDC efficiency versus LHRS momentum (systematic uncertainty)



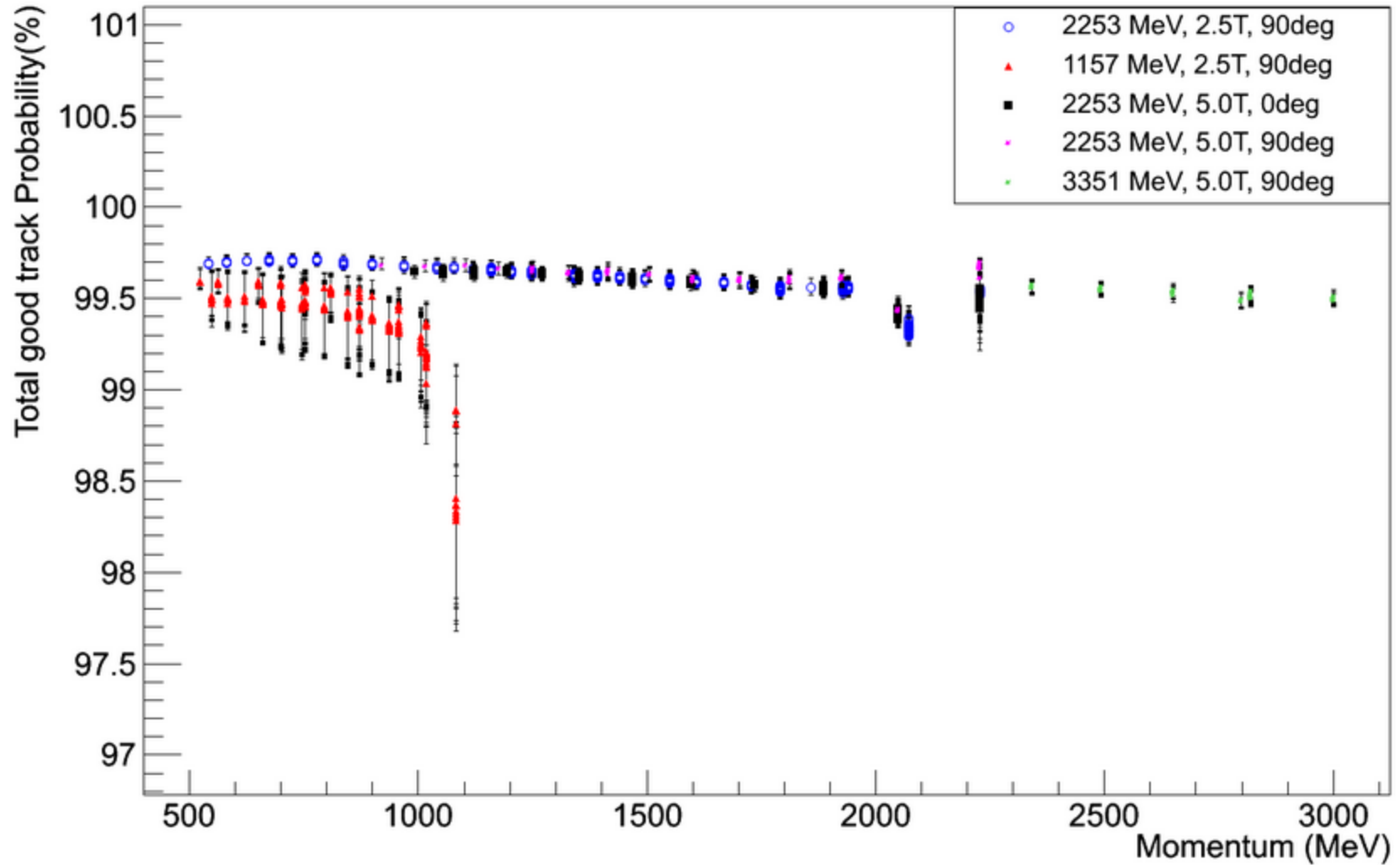
Previous study with background cut added: the center value consider one-track inefficiency

LHRS VDC efficiency versus LHRS momentum (systematic uncertainty)



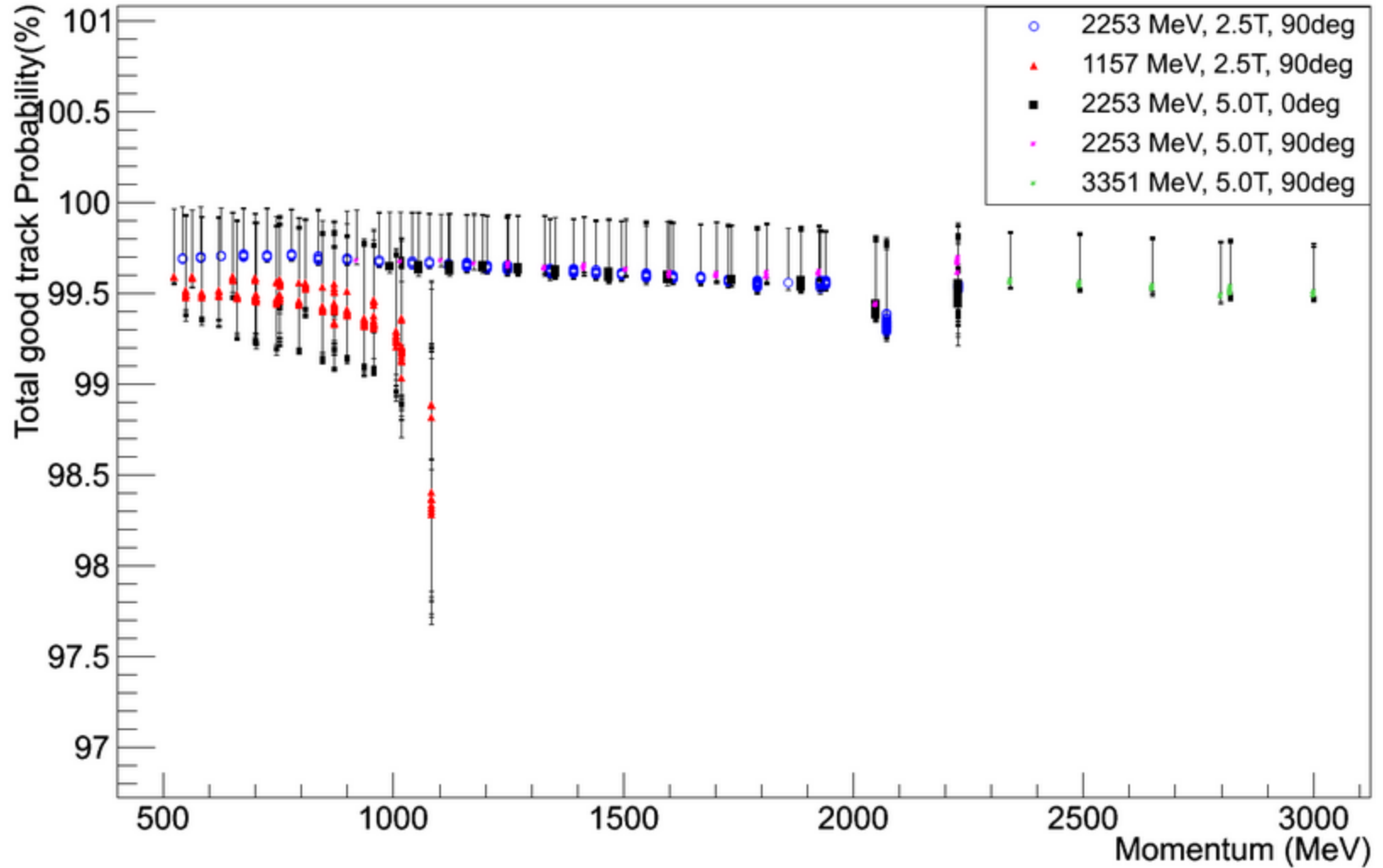
New study: Option 1

LHRS VDC efficiency versus LHRS momentum (systematic uncertainty)



New study: Option 2

LHRS VDC efficiency versus LHRS momentum (systematic uncertainty)



New study: Option 3

LHRS VDC efficiency versus LHRS momentum (systematic uncertainty)

